

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S13	2	("20040111231" or "20040128567") and (wafer die substrat\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/18 15:00
S14	1	("20040111231" or "20040128567") and (wafer die substrat\$3 chip) and (lot batch)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/18 13:04
S15	420	(test\$3 verif\$7 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) with (wafer near3 (lot batch\$2 lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplici\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) and (test\$3 verif\$7 analy\$4 check\$3 valu\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) same (pluralit\$3 many multiple collection multiplici\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/18 16:04
S16	316	(test\$3 verif\$7 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) with (wafer near3 (lot batch\$2 lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplici\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) and ((test\$3 verif\$7 analy\$4 check\$3 valu\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) same (pluralit\$3 many multiple collection multiplici\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage)) and ((determine\$5 find\$3 obtain\$3 evaluat\$3 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (voltage))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/18 16:07

EAST Search History

S17	12	(test\$3 verif\$7 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) with (wafer near3 (lot batch\$2 lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplicit\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) and ((test\$3 verif\$7 analy\$4 check\$3 valuat\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) same (pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage)) and ((determine\$5 find\$3 obtain\$3 evaluat\$3 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (operation\$3 near (voltage)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/18 16:14
S18	219	(test\$3 verif\$7 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) near4 (wafer near3 (lot batch\$2 simultaneous\$2 lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplicit\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) and ((test\$3 verif\$7 analy\$4 check\$3 valuat\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) same (pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage)) and ((determine\$5 find\$3 obtain\$3 evaluat\$3 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (voltage))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/18 16:21

EAST Search History

S19	137	(test\$3 verif\$7 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) near4 (wafer near3 (lot batch\$2 simultaneous\$2 lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplicit\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) and ((test\$3 verif\$7 analy\$4 check\$3 valuat\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) with (pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage)) and ((determine\$5 find\$3 obtain\$3 evaluat\$3 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (voltage))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/18 16:23
S20	10	(test\$3 verif\$7 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) near4 (wafer near3 (lot batch\$2 simultaneous\$2 lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplicit\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) same ((test\$3 verif\$7 analy\$4 check\$3 valuat\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) with (pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage)) and ((determine\$5 find\$3 obtain\$3 evaluat\$3 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (voltage))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/19 09:43

EAST Search History

S21	172	(test\$3 verif\$7 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) near2 (wafer near3 (lot batch\$2 simultaneous\$2 lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplicit\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) and ((test\$3 verif\$7 analy\$4 check\$3 valuat\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) same (pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage)) and ((determine\$5 find\$3 obtain\$3 evaluat\$3 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (voltage))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/19 10:03
S22	10	(test\$3 verif\$7 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) near (wafer near3 (lot batch\$2 simultaneous\$2 lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplicit\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) same ((test\$3 verif\$7 analy\$4 check\$3 valuat\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) same (pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage)) and ((determine\$5 find\$3 obtain\$3 evaluat\$3 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (voltage))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/19 10:08
S23	1	"20050172182" and (relativ\$2 near significance)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/19 10:39

EAST Search History

S24	60	(test\$3 verif\$7 evaluat\$3 inspect\$3 simulat\$3 sort\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) with (wafter prob\$3) same ((test\$3 verif\$7 analy\$4 simulat\$3 analy\$4 check\$3 valu\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) with (pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage)) and (wafer near2 (lot batch\$2 simultaneous\$2 set lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplicit\$3 pack pile plent\$3 collectiv\$3 numerous\$2))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/19 10:56
S25	7	(test\$3 verif\$7 evaluat\$3 inspect\$3 simulat\$3 sort\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) with (wafter prob\$3) same ((test\$3 verif\$7 analy\$4 simulat\$3 analy\$4 check\$3 valu\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) with (pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage)) and (wafers near2 compar\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/19 11:00
S26	140	(test\$3 verif\$7 evaluat\$3 inspect\$3 simulat\$3 sort\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) with wafer with ((pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near2 (voltage))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/19 11:03
S27	112	S26 and @ad<"20040115"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/19 11:12

EAST Search History

S28	1	(test\$3 verif\$7 evaluat\$3 inspect\$3 simulat\$3 sort\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) with (wafer near (lot lots batch\$2 collection set)) with ((pluralit\$3 many multiple collection multiplici\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near2 (voltage))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/19 11:04
S29	3690	((wafer near (lot batch\$2 simultaneous\$2 set lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplici\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) with (test\$3 verif\$7 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/19 11:14
S30	1939	((wafer near (lot batch\$2 simultaneous\$2 set lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplici\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) NEAR3 (test\$3 verif\$7 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/19 11:14
S31	871	((wafer near (lot batch\$2 simultaneous\$2 set lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplici\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) NEAR (test\$3 verif\$7 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/19 12:23

EAST Search History

S32	168	((wafer near (lot batch\$2 simultaneous\$2 set lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplici\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) with (test\$3 verif\$7 simulat\$3 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc)) and ((test\$3 verif\$7 analy\$4 check\$3 simulat\$3 valuat\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) with (pluralit\$3 many multiple collection multiplici\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/19 12:26
S33	43	((wafer near (lot batch\$2 simultaneous\$2 set lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplici\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) with (test\$3 verif\$7 simulat\$3 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc)) and ((test\$3 verif\$7 analy\$4 check\$3 simulat\$3 valuat\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) with (pluralit\$3 many multiple collection multiplici\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage)) and ((optimum optimal ideal favorable best nominal) with (voltag\$2))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/19 12:33
S34	28	S33 and @ad<"20040115"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/19 12:28

EAST Search History

S35	24	((wafer near (lot batch\$2 simultaneous\$2 set lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplici\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) with (test\$3 verif\$7 simulat\$3 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc)) and ((test\$3 verif\$7 analy\$4 check\$3 simulat\$3 valuat\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) with (pluralit\$3 many multiple collection multiplici\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage)) and ((optimum optimal ideal favorable best nominal) near3 (voltag\$2))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/19 12:34
S36	25209373	@ad<"20040115"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/19 12:35
S37	17	S35 and S36	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/19 12:35
S38	5	(US-20040128567-\$ or US-20050050172-\$ or US-20030056029-\$).did. or (US-6414508-\$ or US-5457695-\$). did.	US-PGPUB; USPAT	OR	ON	2006/08/19 12:42
S39	10	("5519333" "5521524" "5742177" "5889408" "6140832" "6147316" "6175244" "6175812" "6230293").PN. OR ("6414508"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/08/19 12:55

EAST Search History

S40	10	((wafer near (lot batch\$2 simultaneous\$2 set lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplicit\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) near4 (test\$3 verif\$7 simulat\$3 reliabilit\$3 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc)) and ((test\$3 verif\$7 analy\$4 check\$3 simulat\$3 valuat\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) with (pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage)) and ((determine\$5 find\$3 obtain\$3 evaluat\$3 identif\$7 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (voltage\$2) with (optimal optimum nominal favorable best ideal))	US-PGPUB; USPAT; USOCR	OR	ON	2006/08/19 13:04
S41	8	((wafer near (lot batch\$2 simultaneous\$2 set lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplicit\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) near4 (test\$3 verif\$7 simulat\$3 reliabilit\$3 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc)) same ((determine\$5 find\$3 obtain\$3 evaluat\$3 identif\$7 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (voltage\$2) with (optimal optimum nominal favorable best ideal))	US-PGPUB; USPAT; USOCR	OR	ON	2006/08/19 13:18

EAST Search History

S42	26	(wafer near5 (test\$3 verif\$7 evaluat\$3 inspect\$3 simulat\$3 sort\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc)) and ((pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near5 (voltag\$2)) and ((determine\$5 find\$3 obtain\$3 second evaluat\$3 identif\$7 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (voltag\$2) near3 (optimal optimum nominal favorable best ideal)) and ((determine\$5 find\$3 obtain\$3 detect\$3 evaluat\$3 identif\$7 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (failur\$3 error\$3 deficienc\$3 fault glitch\$2)) and ((wafer with (lot batch\$2 sets lots pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplicit\$3 pack pile plent\$3 collectiv\$3 numerous\$2)))	US-PGPUB; USPAT; USOCR	OR	ON	2006/08/19 13:21
S43	13	S42 and S36	US-PGPUB; USPAT; USOCR	OR	ON	2006/08/19 13:26

EAST Search History

S44	13	(wafer near5 (test\$3 verif\$7 reliabilit\$3 evaluat\$3 inspect\$3 simulat\$3 sort\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc)) and ((pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near5 (voltag\$2)) and ((determine\$5 find\$3 obtain\$3 second evaluat\$3 identif\$7 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (voltag\$2) near3 (optimal optimum nominal favorable best ideal)) and ((determine\$5 find\$3 obtain\$3 detect\$3 evaluat\$3 identif\$7 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (failur\$3 error\$3 deficienc\$3 fault glitch\$2)) and ((wafer with (lot batch\$2 sets lots pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplicit\$3 pack pile plent\$3 collectiv\$3 numerous\$2))) and @ad<"20040115"	US-PGPUB; USPAT; USOCR	OR	ON	2006/08/19 13:30
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EAST Search History

S45	4	(wafer near5 (test\$3 verif\$7 reliabilit\$3 evaluat\$3 inspect\$3 simulat\$3 sort\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc)) and ((pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near5 (voltag\$2)) and ((determine\$5 find\$3 obtain\$3 second evaluat\$3 identif\$7 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (voltag\$2) near3 (optimal optimum favorable best ideal)) and ((determine\$5 find\$3 obtain\$3 detect\$3 evaluat\$3 identif\$7 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (failur\$3 error\$3 deficienc\$3 fault glitch\$2)) and ((wafer with (lot batch\$2 sets lots pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplicit\$3 pack pile plent\$3 collectiv\$3 numerous\$2))) and @ad<"20040115"	US-PGPUB; USPAT; USOCR	OR	ON	2006/08/19 13:31
S46	72	((determine\$5 find\$3 obtain\$3 second evaluat\$3 identif\$7 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (voltag\$2) near3 (optimal optimum favorable best ideal)) and (wafer near5 (test\$3 verif\$7 reliabilit\$3 evaluat\$3 inspect\$3 simulat\$3 sort\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc)) and @ad<"20040115"	US-PGPUB; USPAT; USOCR	OR	ON	2006/08/19 13:32

EAST Search History

S47	48	((determine\$5 find\$3 obtain\$3 second evaluat\$3 identif\$7 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (voltag\$2) near3 (optimal optimum favorable best ideal)) and (wafer near5 (test\$3 verif\$7 reliabilit\$3 evaluat\$3 inspect\$3 simulat\$3 sort\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc)) and @ad<"20040115" and ((wafer with (lot batch\$2 sets lots pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplicit\$3 pack pile plent\$3 collectiv\$3 numerous\$2)))	US-PGPUB; USPAT; USOCR	OR	ON	2006/08/19 13:43
S48	4	(test\$3 verif\$7 evaluat\$3 inspect\$3 analy\$4 check\$3 validat\$3 investigat\$3 examin\$5 drc) near (wafer near3 (lot batch\$2 simultaneous\$2 set lots group\$3 pluralit\$3 multiple many collection bundl\$3 bunch load heap cluster\$3 multiplicit\$3 pack pile plent\$3 collectiv\$3 numerous\$2)) and ((test\$3 verif\$7 analy\$4 check\$3 valuat\$3 validat\$3 inspect\$3 investigat\$3 examin\$5 assess\$4 evaluat\$3 drc) with (pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied) near3 (voltage)) and ((determine\$5 find\$3 obtain\$3 evaluat\$3 identif\$7 calculat\$3 ascertain\$3 resolv\$3 decid\$3 choos\$3 select\$3) with (voltage) with (optimal favorable best ideal))	US-PGPUB; USPAT; USOCR	OR	ON	2006/08/19 13:51
S49	113	test\$3 with wafer with (various varying vary varied different\$2 chang\$3 another) with voltage	US-PGPUB; USPAT; USOCR	OR	ON	2006/08/19 13:53
S50	87	S49 and S36	US-PGPUB; USPAT; USOCR	OR	ON	2006/08/19 13:58
S51	55	(wafer near2 (lots lot batch\$2)) with electrical with test\$3 and S36	US-PGPUB; USPAT; USOCR	OR	ON	2006/08/19 14:06

EAST Search History

S52	13	S51 and Voltag\$2 with (pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied various)	US-PGPUB; USPAT; USOCR	OR	ON	2006/08/19 14:09
S53	1	"6414508".pn.	US-PGPUB; USPAT; USOCR	OR	ON	2006/08/19 14:05
S54	1	"6414508".pn. and voltage	US-PGPUB; USPAT; USOCR	OR	ON	2006/08/19 14:05
S55	91	(wafer near2 (lots lot batch\$2)) with sort\$3 and S36	US-PGPUB; USPAT; USOCR	OR	ON	2006/08/19 14:06
S56	8	S55 and Voltag\$2 with (pluralit\$3 many multiple collection multiplicit\$3 various different chang\$3 plent\$3 collectiv\$3 numerous\$2 another several vary\$3 assort\$3 varied various)	US-PGPUB; USPAT; USOCR	OR	ON	2006/08/19 14:17
S57	1	"20040128567" and (wafer)	US-PGPUB; USPAT; USOCR	OR	ON	2006/08/19 14:18
S58	1	"20040111231" and opti\$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/19 15:21
S59	1	"20040111231" and (Fail\$4 error\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/19 15:22